Content

Course Code	Course Name	Semester	Theory	Practice	Lab	Credit	ECTS
INF 511	Data Science	1	3	0	0	3	6

Prerequisites	
Admission Requirements	

Language of Instruction	English
Course Type	Elective
Course Level	Masters Degree
Objective	This course aims to introduce students to the data mining process. The main objectives of the course include understanding and applying data preparation and preprocessing techniques, various data mining algorithms, and the tools used to evaluate their results. The course focuses on standard approaches related to association rule mining, supervised classification, and unsupervised classification (clustering). Basic statistical knowledge is required to understand mining algorithms and quality evaluation tools. In this way, the course aims to enable students to produce practical solutions in the field of data analysis.
Content	- data pre-processing - supervised classification - clustering - complex data mining - results validation and quality assessment
References	1. Data Mining - Practical Machine Learning Tools, 2nd edition, Ian H. Witten & Eibe Frank, Morgan Kaufmann, 2005. 2. Neural Networks - A Comprehensive Foundation, 2nd edition, Simon Haykin, Pearson/Prentice Hall,1999. 3. Data Mining: Concepts and Techniques, Jiawei Han & Micheline Kamber, Morgan Kaufmann, 2000. 4. Applied Statistics and Probabilities for Engineers, 4th edition, D.C. Montgomery & G.C. Runger, John Willey & sons, 2006. 5. The Elements of Statistical Learning: Data Mining, Inference, and Prediction, 2nd edition, T. Hastie, R. Tibshirani & J. Friedman, Springer, 2009.

Theory Topics

Week	Weekly Contents
1	Introduction
2	Data preparation
3	Association rules and a priori algorithm
4	FP-trees and complex rules
5	Decision trees and naïve Bayes classifier
6	Statistical regression and Bayesian networks
7	Neural networks and other classifiers
8	Quality assessment on classification results
9	Classifier comparison
10	Distance and partitioning
11	Hierarchical clustering methods
12	Clustering with grids and density

Week	Weekly Contents
13	Model-based processing
14	Outliers detection